

<b>Notice of References Cited</b>				Application No. <b>09-788,629</b>		Applicant(s) <b>Usui et. al</b>	
				Examiner <b>George Gaudreau</b>		Group Art Unit <b>1763</b>	
U.S. PATENT DOCUMENTS							
*	DOCUMENT NO.	DATE	NAME			CLASS	SUBCLASS
A	<b>5,627,640</b>	<b>5-97</b>	<b>Chang et al</b>			<b>356</b>	<b>31C</b>
B							
C							
D							
E							
F							
G							
H							
I							
J							
K							
L							
M							
FOREIGN PATENT DOCUMENTS							
*	DOCUMENT NO.	DATE	COUNTRY	NAME		CLASS	SUBCLASS
N	<b>58-144,476</b>	<b>8-931</b>	<b>Japan</b>	<b>Watanabe et al</b>			
O							
P							
Q							
R							
S							
T							
NON-PATENT DOCUMENTS							
*	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)					DATE	
U	<b>"Use of a Light Emitting Diode As A Current Sensor For Electrostatic Double Probes"; Rev. of Sci. Instru., (2-87),</b>						
W	<b>Vol 58, no. 2, pp. 315-317; Tondys et. al</b>						
W	<b>"A Plasmascope Using Light Emitting Diodes"; Rev. of Sci. Instru.; (1-74); Vol 45, no. 1; pp 57-59; Ejima et. al</b>						
X							

\* A copy of this reference is not being furnished with this Office action.  
(See Manual of Patent Examining Procedure, Section 707.05(a).)